Rensselaer Polytechnic Institute

VLSI Design
ECSE 4220

Report

Project #2
Final Design Write-up Assignment

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0. Introduction

Throughout this report, the Cadence IC design tool was used to build and simulate f=(AB+C)', using 3 pfets and 3 nfets. First, an ideal version of this circuit was built, after which a real-world simulation was compared. The circuit was first tested in ideal circumstances, after which a layout was built upon it but using real-world setbacks, such as parasitic capacitance and resistance. The responses were then compared and a conclusion was drawn.

1. Circuit Schematic

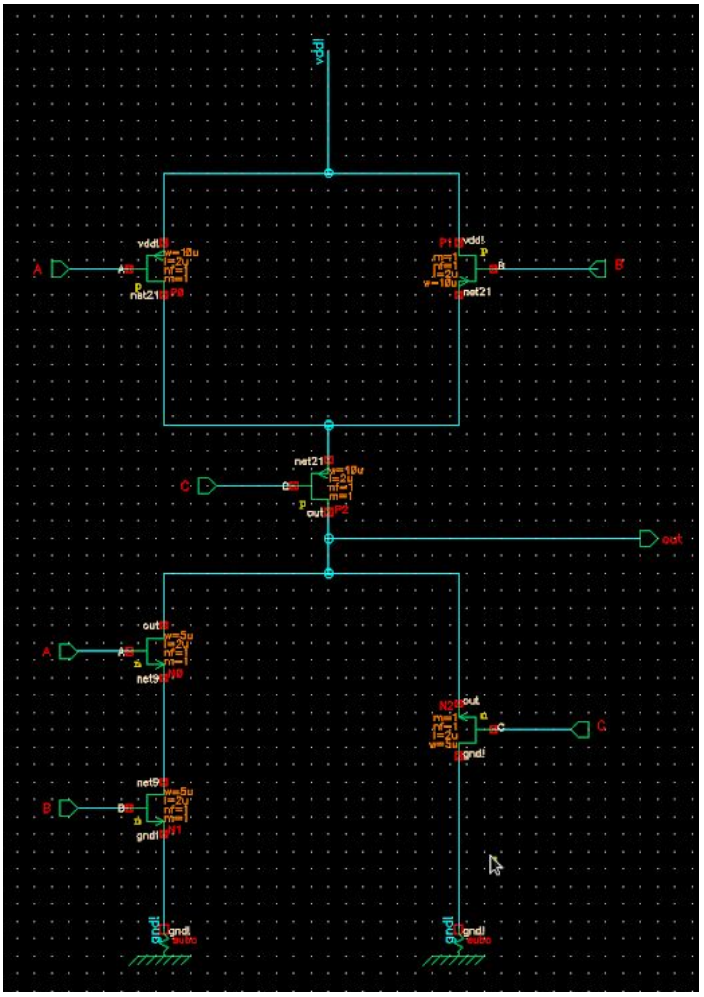

Figure 1: f=(AB+C)' schematic

```
t
mouseAddPt
t
cancelEnterFun()
t
nil
cancelEnterFun()
nil
schHiCheckAndSave()
Extracting "cadence2_design schematic"
Schematic check completed with no errors.
"vlsi_cadence2 cadence2_design schematic" saved.
t
schZoomFit(1.0 0.9)
t
```

Figure 2: Check and Save output

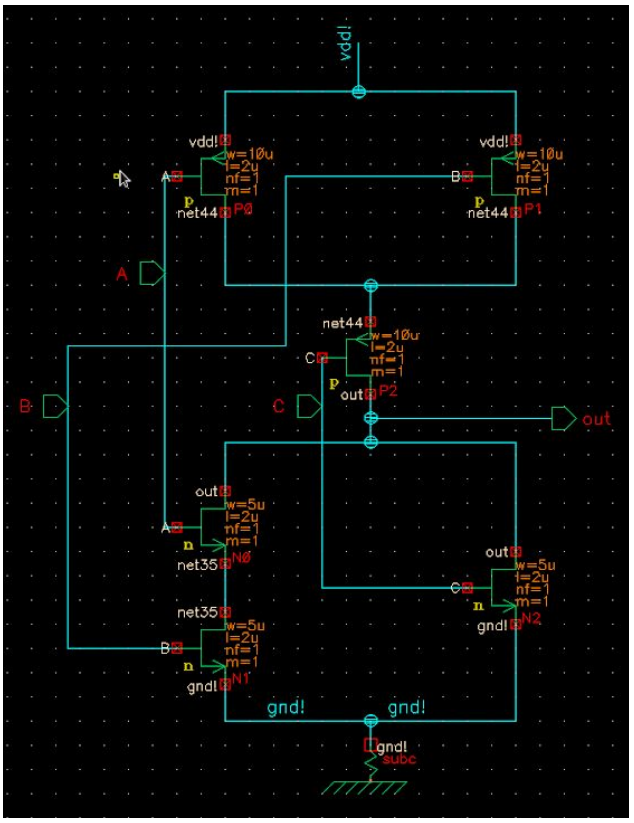

Figure 3: Updated Schematic with no repeating pins

Figure 1 above displays the initial built circuit in Cadence. This circuit later failed due to wire and pin names that were the same and was later changed to the circuit displayed in Figure 3. As can be seen in Figure 2, at the final 'Check and Save' run, there were no errors found by the program. The same numbers for the pfet and nfet lengths were used as in the tutorial.

2. **Schematic Simulation Results**

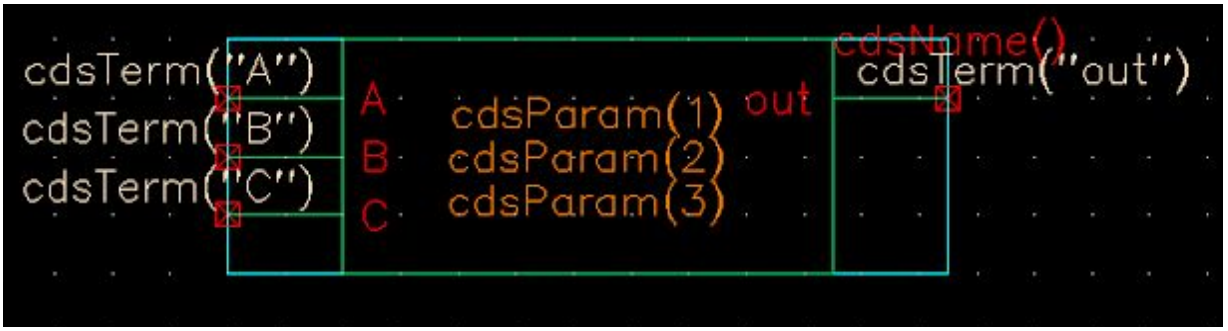

Figure 4: Confirmation of symbol creation

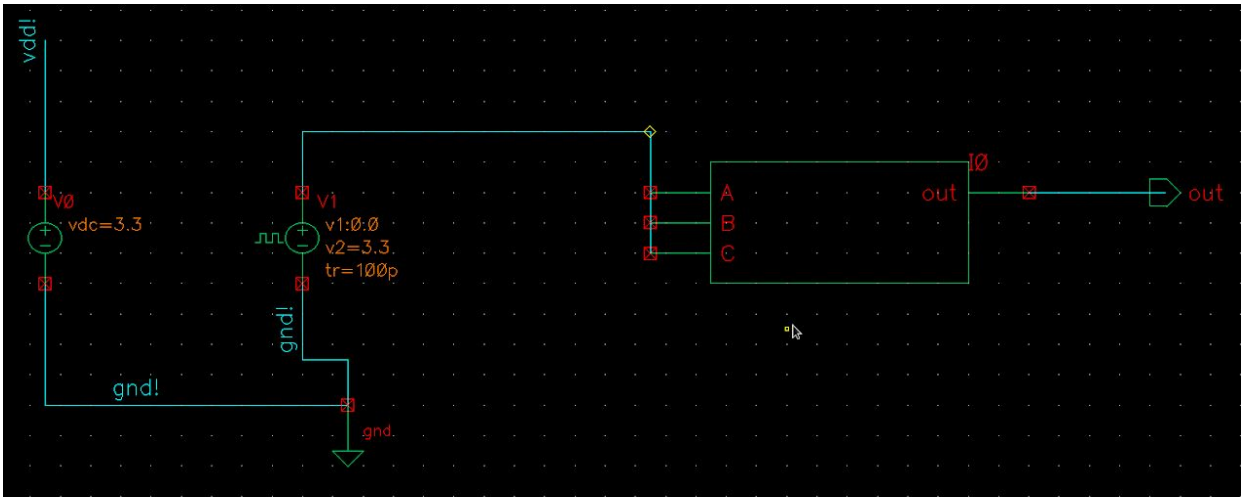

Figure 5: Schematic testbench circuit setup

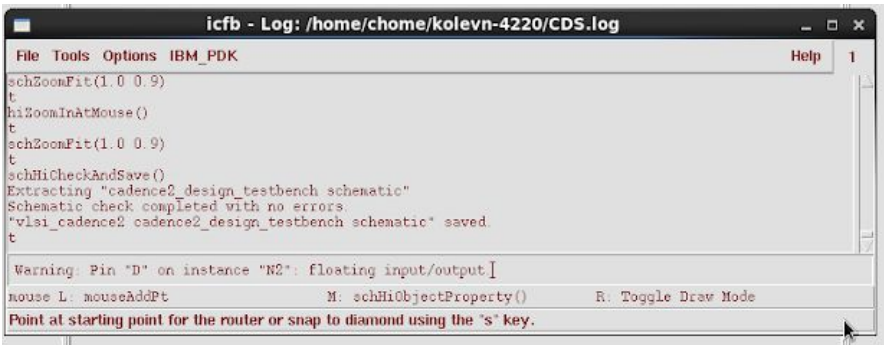

Figure 6: Schematic testbench circuit 'Check and Save' result

For the simulation, a testbench cellview was built to implement the (AB+C)' circuit previously built as a schematic. Additionally, ground, VDC and VPULSE sources were added. The values used for the voltage sources were the same as provided in the class tutorial. Once, this was built anc checked successfully, the simulation was initiated.

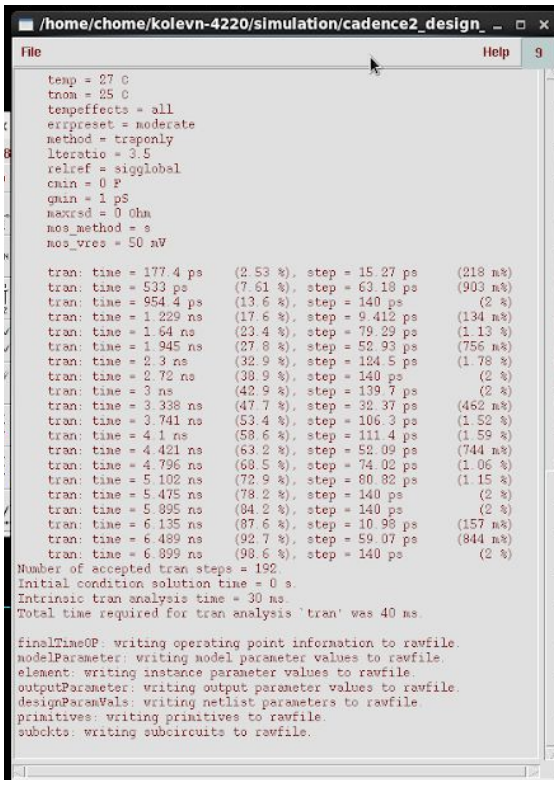

Figure 7: Simulation/Testbench netlist results

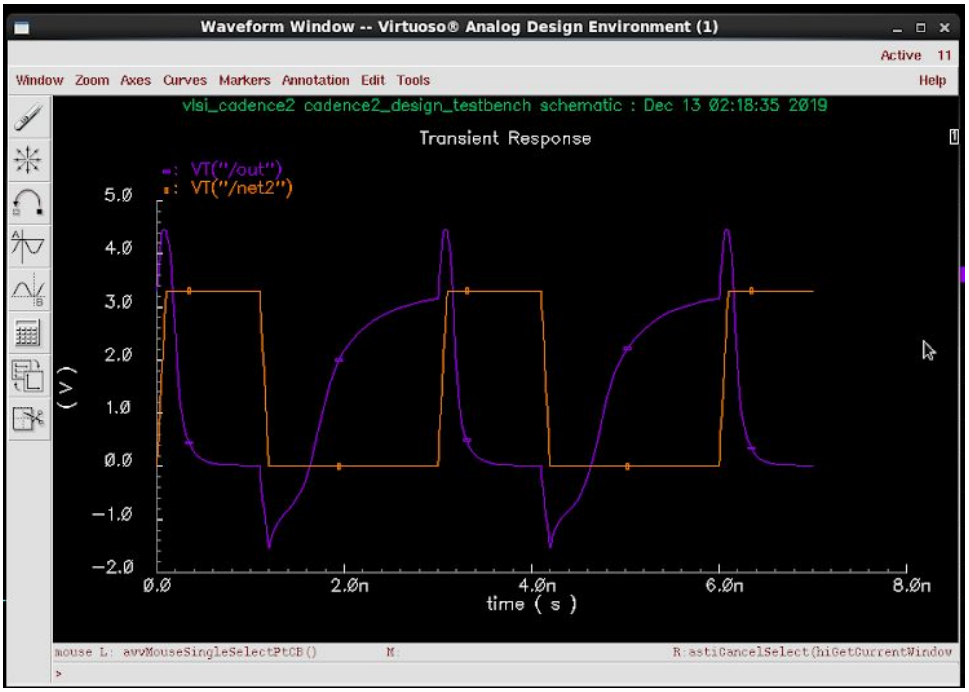

Figure 8: Schematic simulation result

In Figure 8 above, the results of the simulation can be observed. It was done with a 7ns stop time and done for the schematic file of the circuit.

3. **Full Layout**

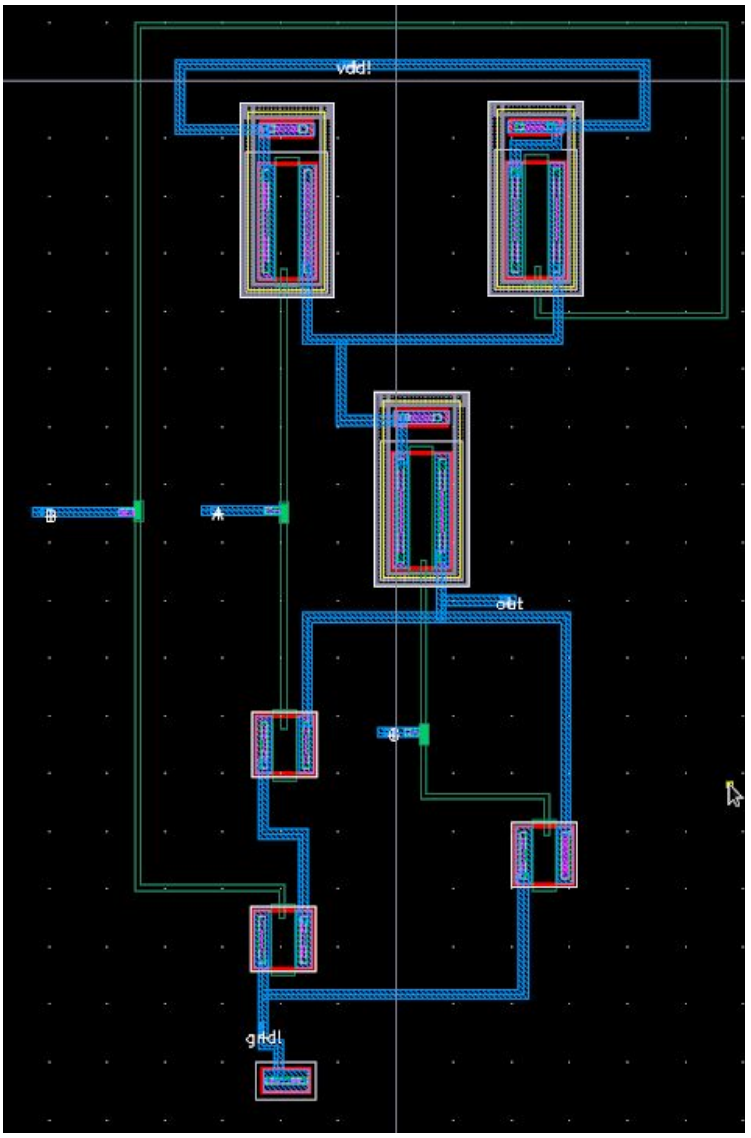

Figure 9: Full layout of f=(AB+C)' circuit, original

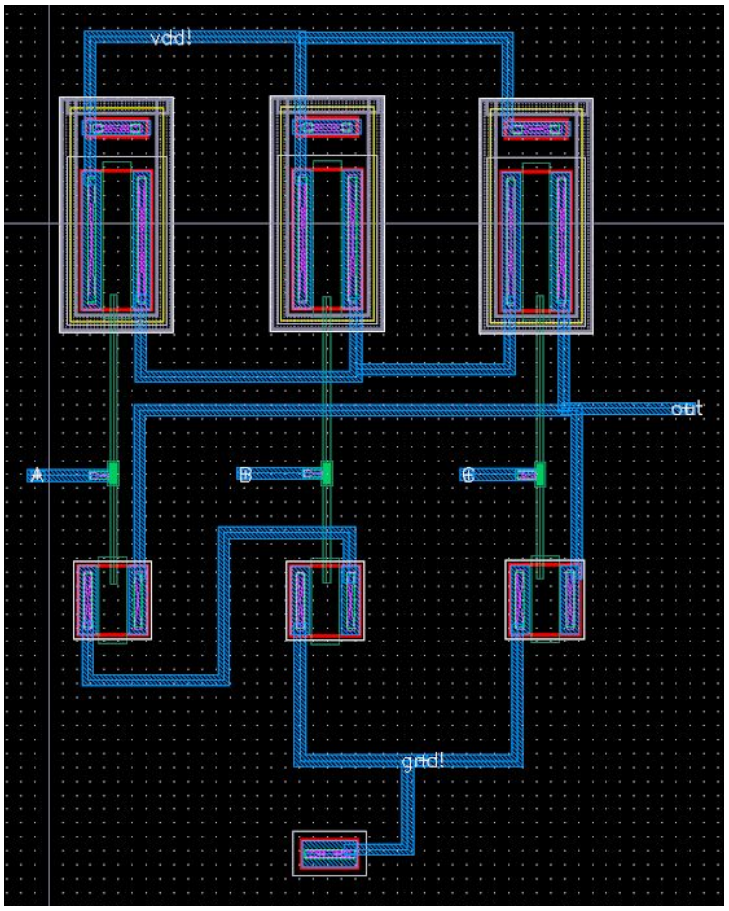

Figure 10: Full layout of modified f=(AB+C)' circuit

The layout of the circuit was initially built as shown in Figure 9 and worked as intended but in an effort to improve legibility and design, the design was later modified to what can be observed in Figure 10. This design was deemed more intuitive and easier to visualize in a physical implementation.

4. **Design Rule Check (DRC) of the layout**

Figure 11: DRC check of result

In Figure 10 above is the compact cell constructed, which passes DRC, as can be seen in Figure 11 (with only two INFO errors, which are stated as normal and expected as in the tutorial document). While DRC and LVS checks passed, there was an initial netlist mismatch with the schematic file, which was later resolved. It was due to wiring issues and discrepancies between the layout and schematic. This was fixed with the design change mentioned in Section 3 above.

5. **Layout Extraction and Layout vs. Schematic (LVS) check result**

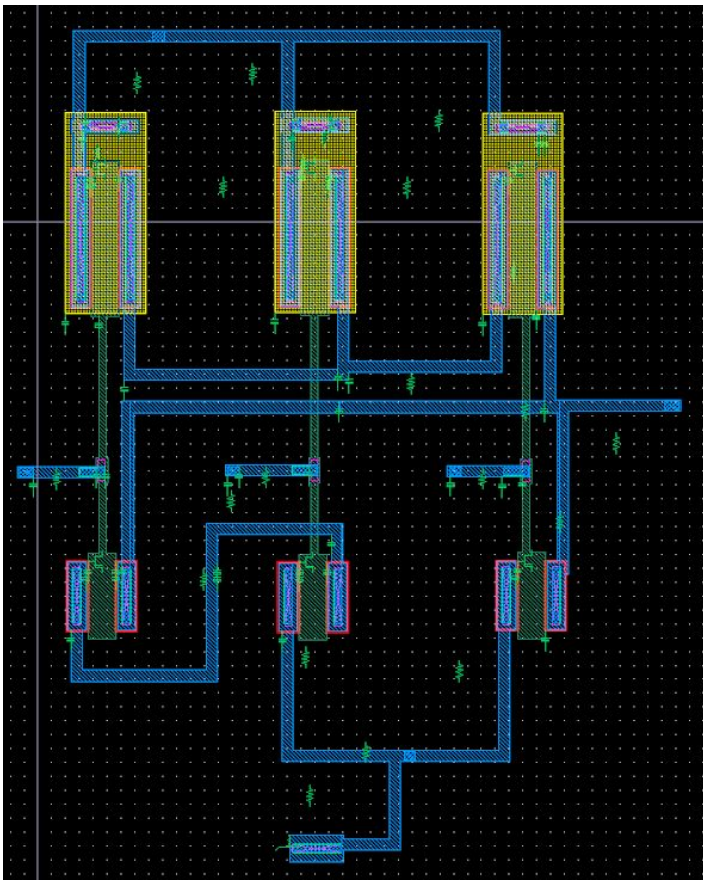

Figure 12: Extracted view of the layout

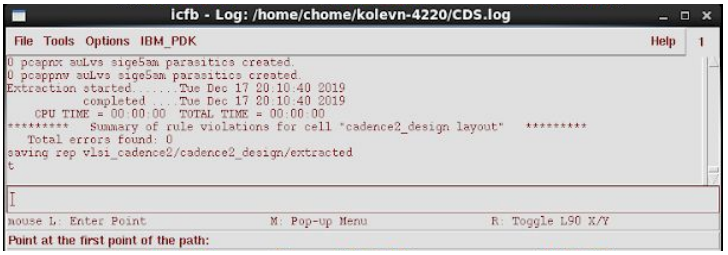

Figure 13: Extraction error results

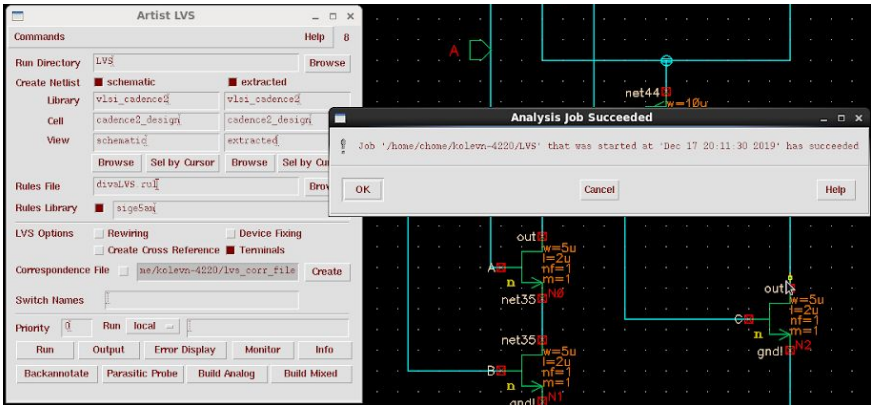

Figure 14: LVS check results

The layout extraction can be seen in Figure 12 above. It came out with no errors, as can be seen in Figure 13. Afterwards, the LVS check was run on the layout and succeeded once problems such as misaligned contacts were fixed. Once fixed, the layout passed through DRC and was re-extracted, the LVS check was successful, as can be observed in Figure 14.

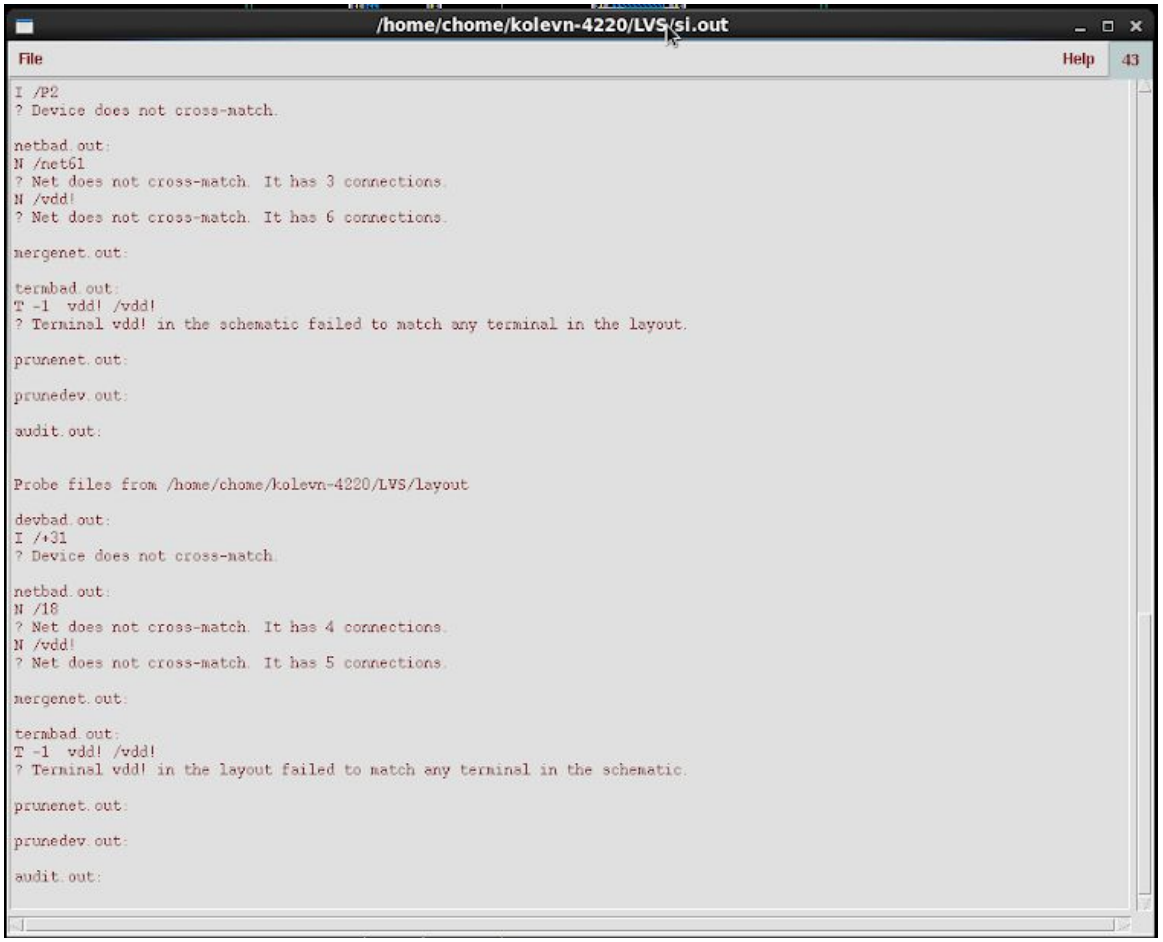

Figure 15: Netlists match check, original

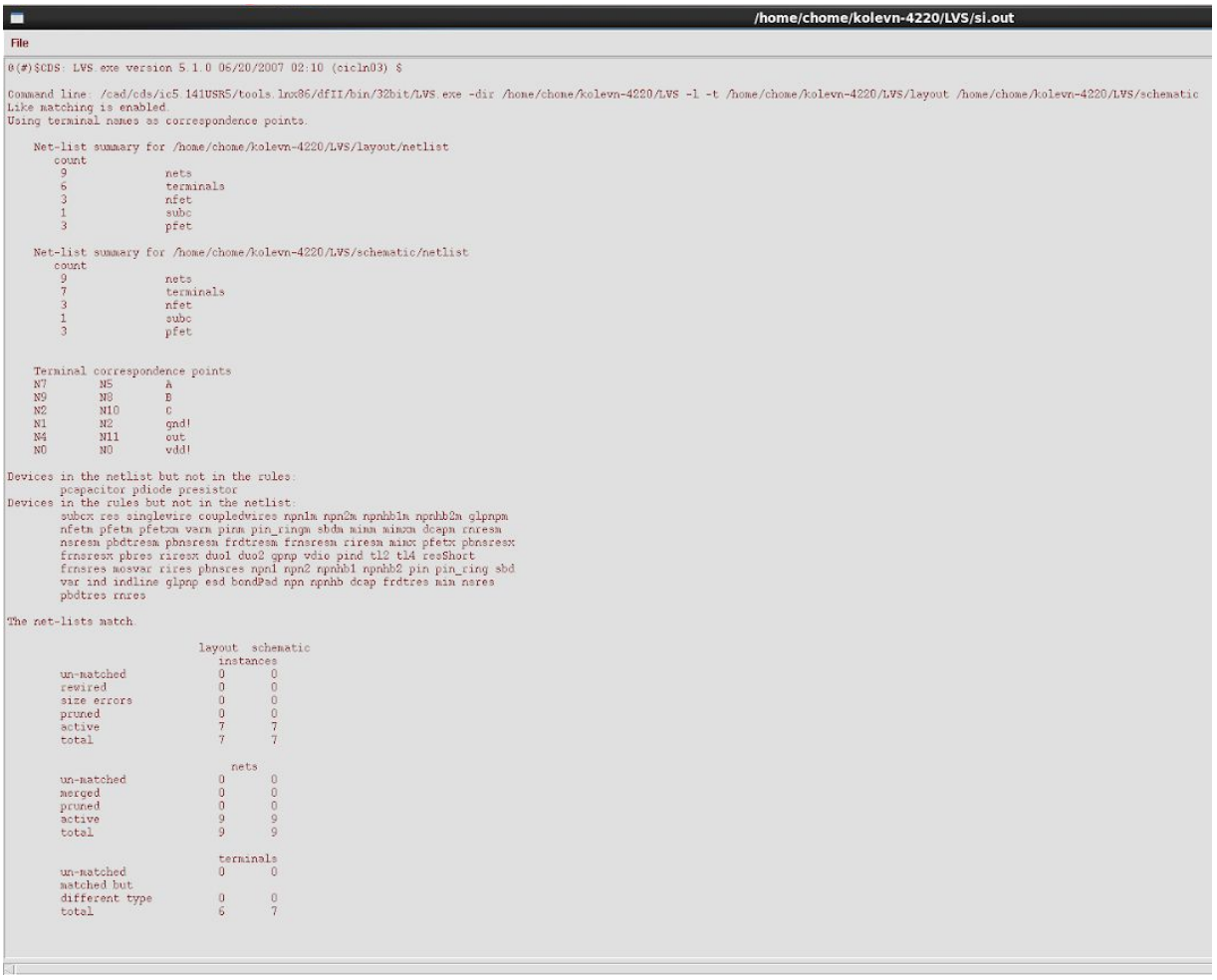

Figure 16: Net-list match check, fixed

Lastly, before attempting the post-layout simulation, the si.out file was checked to ensure that the netlists of the schematic and layout matched, in order to ensure that the simulation would run successfully. They initially did not due to misaligned wires that could not be adjusted without re-doing the layout schematic. This error prevented further build-analog actions, since parts of the LVS tests were failing. Therefore, the layout was redesigned to better match the schematic and re-extracted, as mentioned above. This redesign fixed the mismatch error, as can be seen in Figure 16 above, and allowed for the simulation to be completed. The process of simulation build can be observed in the following section and figures.

6. Post-Layout Simulation

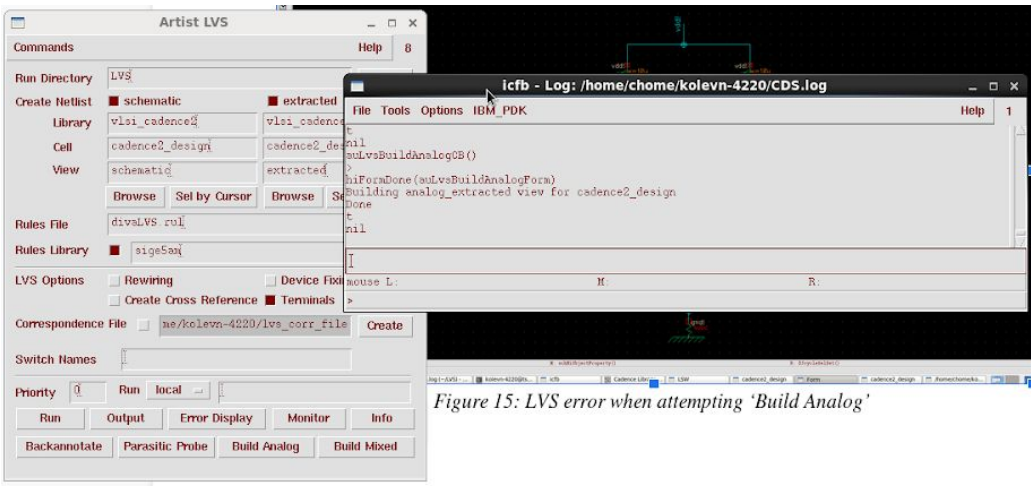

Figure 15: LVS error when attempting 'Build Analog'

Figure 17: Build Analog after netlist match

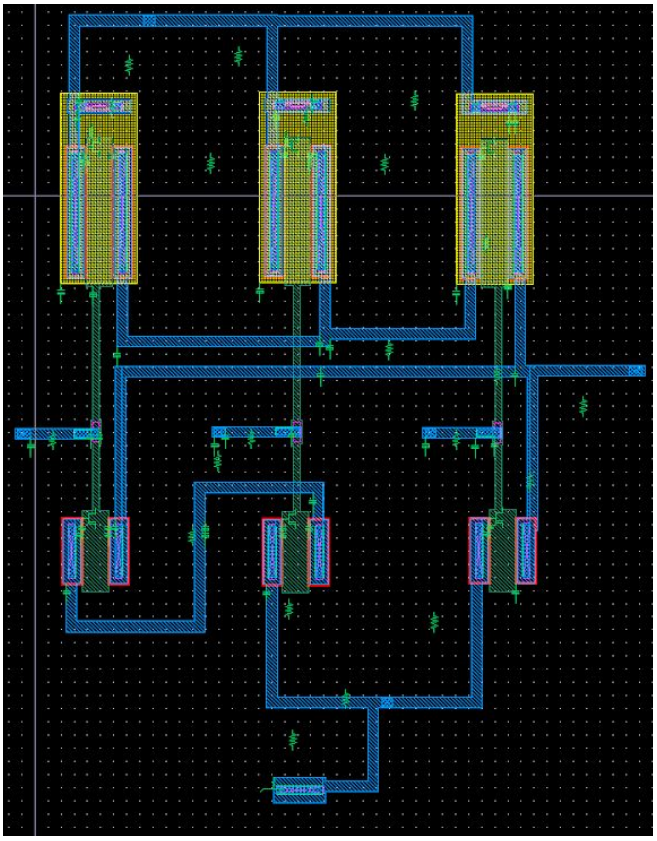

Figure 18: Analog_extracted file view

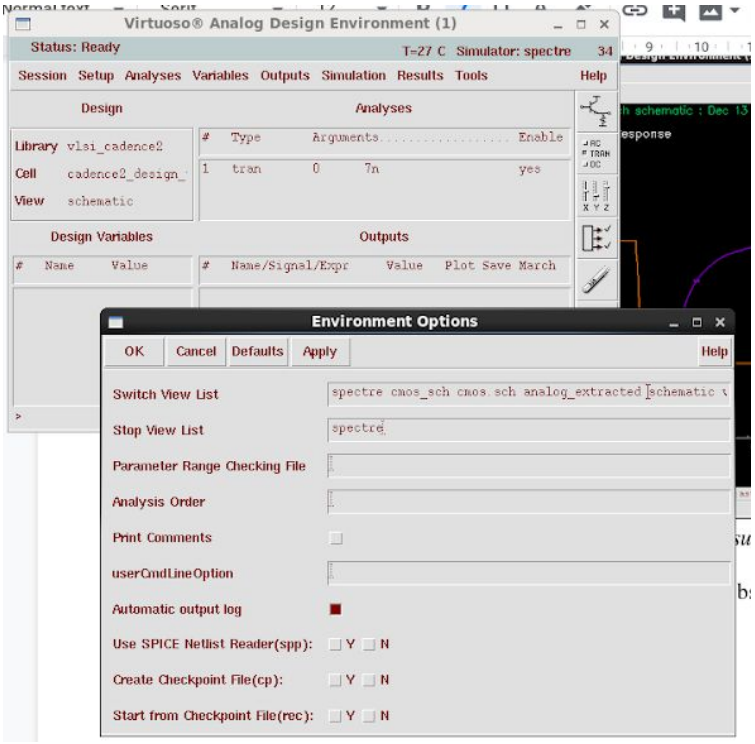

Figure 19: Changing testbench environment options to analog_extracted file

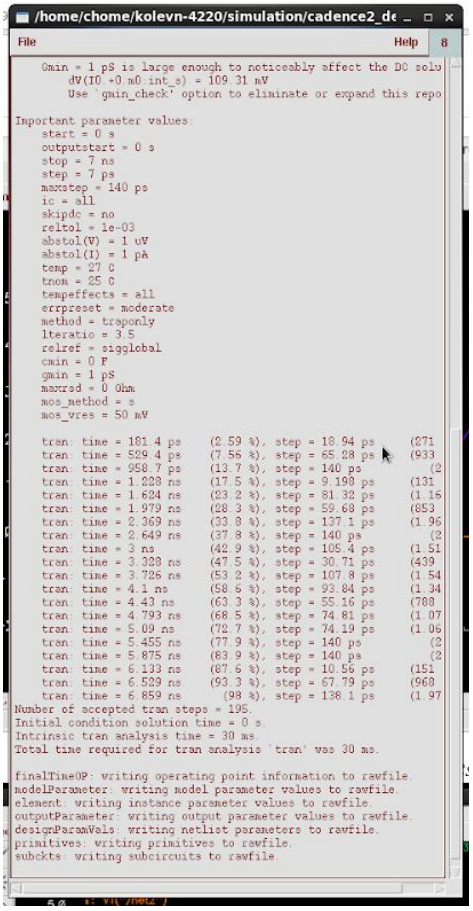

Figure 20: Simulation log check successful

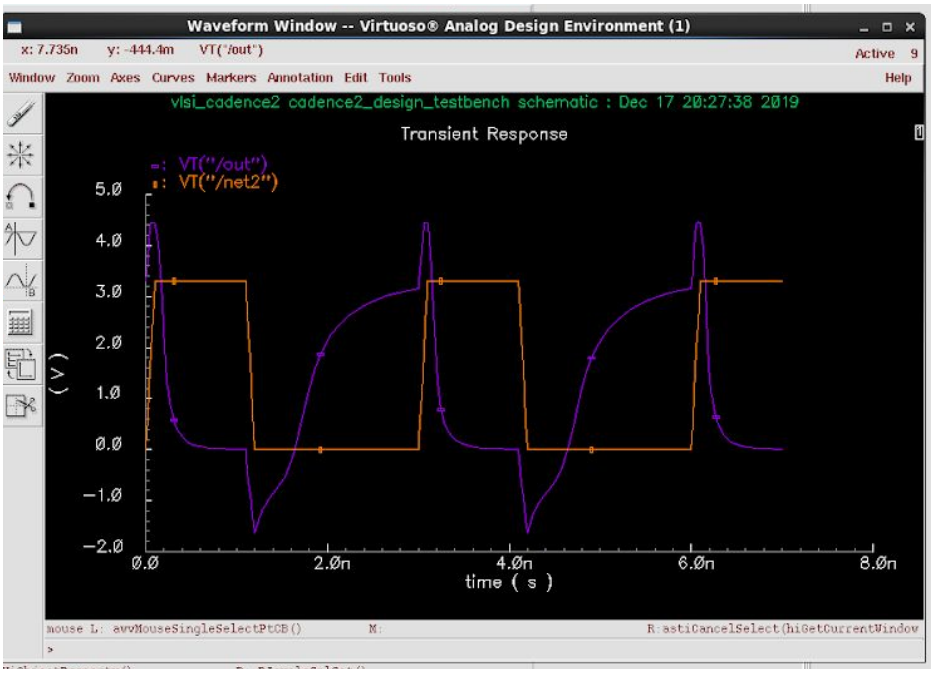

Figure 21: Analog_extracted post-simulation result

In the figures above, the process of building the analog_extracted view. The process begins with clicking the Build Analog option on the Artist LVS window, after which a new extracted view is built. Once this is done, the simulation view list is modified to include this analog_extracted view and the post-layout simulation is run. This post-layout simulation can be seen in Figure 21 above. It differs from the original because the analog_extracted file, which is built upon the layout, is referred to when running the simulation, as opposed to the base schematic file.

7. Simulation Results

As can be seen through the simulation results of the schematic and extracted analog files, an analysis of the transient response of f=(AB+C)' can be made. This analysis can be further built upon the previous simulation with an inverter, namely that rise and fall times would be affected due to the parasitic elements present in the extracted layout file. This speculation ends up being correct, as can be observed in the two simulation images. Therefore, it can once again be concluded that parasitic elements change the behavior of circuits and should be accounted for prior to implementations. As this circuit contains a logic AND and OR gate, rather than just an inverter, the differences are more noticeable in the final simulation, further supporting the argument that larger and more complex circuits should definitely be simulated prior to physical implementation, since ideal behavior cannot be assumed in real-world situations.

8. Conclusion

Through these past two exercises in simulating an inverter and (AB+C)', it can be predicted that while parasitic capacitance and resistance change the ideal response, they do not fundamentally change how the pre-analog circuit behaves. Though the circuit behaves differently due to its rise and fall times differing from ideal times, the output response remains the same in form and does not fundamentally change its main functionality or

transient response. The response being altered due to parasitic elements is expected, based on the parasitic element definition studied in class. Lastly, these slight changes should definitely be noted and taken into account when building real-world circuits, as they can change a circuit's response, leading to unexpected or unwanted results, especially when combining with more circuit elements or other factors that are not accounted for when designing on paper.